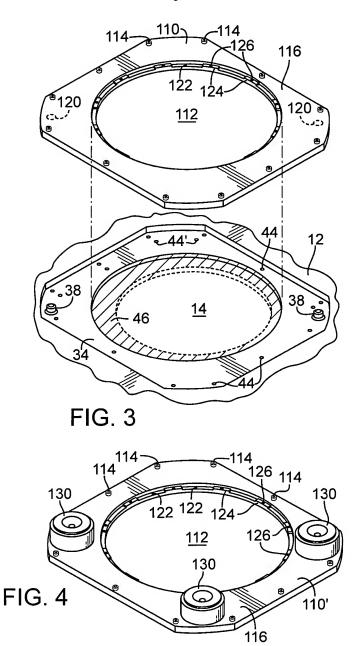


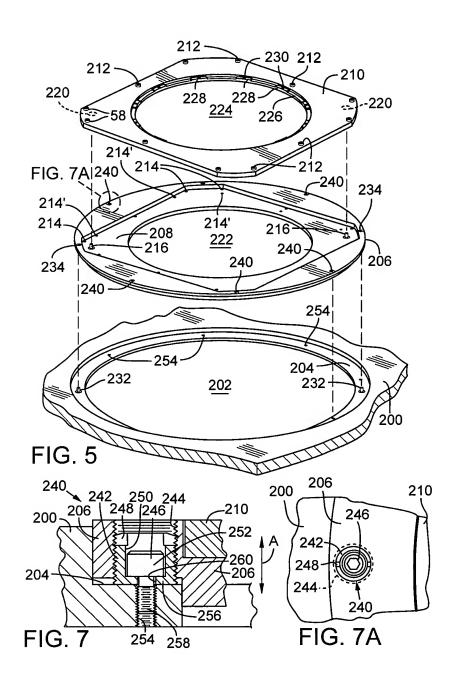
FIG. 2

Attorney Ref. No. 6427-65559
Express Mail No. EV339208764US
Entitled: APPARATUS AND METHOD FOR USE IN TESTING A SEMICONDUCTOR WAFER
Inventor(s): James E. Orsillo

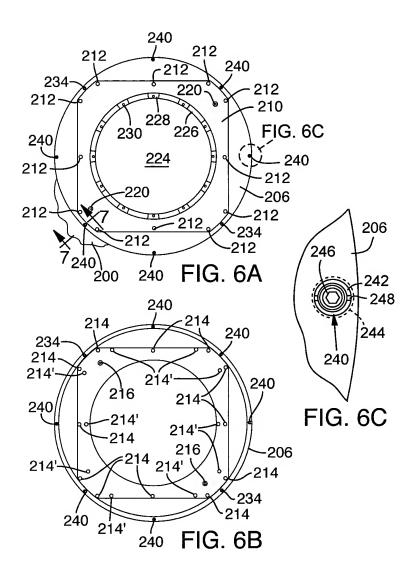
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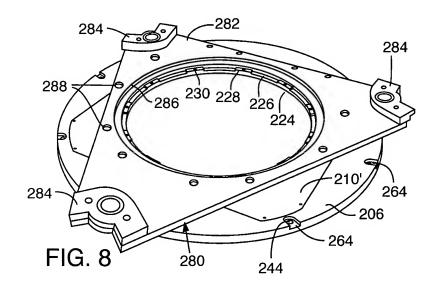


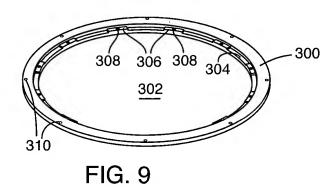
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